

FROMMER LAWRENCE & HAUG LLP

745 FIFTH AVENUE NEW YORK, NEW YORK 10151

JC918 U.S. PTO
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WILLIAM S. FROMMER
WILLIAM F. LAWRENCE
EDGAR H. HAUG
MATTHEW K. RYAN
BARRY S. WHITE
THOMAS J. KOWALSKI
JOHN R. LANE
DENNIS M. SMID*
DANIEL G. BROWN
BARBARA Z. MORRISSEY
STEVEN M. AMUNDSON
MARILYN MATTHES BROGAN
JAMES K. STRONSKI
CHARLES J. RAUBICHECK
GRACE L. PAN*
GORDON KESSLER
MARK W. RUSSELL*
JEFFREY A. HOVDEN

A. THOMAS S. SAFFORD
JEROME ROSENSTOCK
RAYMOND R. WITTEKIND, PH.D.
SUSAN K. LEHNHARDT, PH.D.
RICHARD E. PARKE
Of Counsel
BRUNO POLITO
JOE H. SHALLENBURGER
CHRISTIAN M. SMOLIZZA
GLENN F. SAVIT
ROBERT E. COLLETTI
DEXTER T. CHANG
PETER J. WAIBEL
LINDSEY A. MOHLE
DEENA P. LEVY
DARREN M. SIMON
YUFENG LIU, PH.D.
JOHN G. TAYLOR
*Admitted to a Bar
other than New York

March 13, 2001

Assistant Commissioner for Patents
Washington, D.C. 20231

Re: U.S. Patent Application
Applicants: Toshio MAMIYA, Hiroaki YADA, Keitaro YAMASHITA,
Akira MITANI
Our Ref.: 450100-03041

Dear Sir:

Enclosed are papers constituting the above patent application which is being filed under 37 C.F.R. 1.53 without a signed Declaration. Please accord a filing date and a serial number to such application and inform the undersigned thereof so that a signed Declaration and the surcharge required by 37 C.F.R. 1.16(e) may be duly filed.

Please address all correspondence to:

William S. Frommer, Esq.
FROMMER LAWRENCE & HAUG LLP
745 Fifth Avenue
New York, New York 10151

Respectfully,



William S. Frommer
Reg. No. 25,506
Attorney for Applicants
Enclosures